

JCE21 U.S. PTO  
10/05/056  
01/22/02

U.S. UTILITY Patent Application

PATENT NUMBER and  
ISSUE DATE

APPL NUM 10051056	FILING DATE 01/22/2002	CLASS 324	SUBCLASS 338	GAU 2829	EXAMINER Per + NGUYEN J
<b>**APPLICANTS:</b> Asayama Kyoichiro Mitsui Yasuhiro Arakawa Fumiko Kamohara Shiro Ohji Yuzuru					
<b>**CONTINUING DATA VERIFIED:</b>					
<b>** FOREIGN APPLICATIONS VERIFIED:</b> JAPAN 2001-13028 01/22/2001					
PG-PUB DO NOT PUBLISH <input type="checkbox"/>		RESCIND <input type="checkbox"/>			
Foreign priority claimed <input type="checkbox"/> yes <input type="checkbox"/> no		35 USC 119 conditions met <input type="checkbox"/> yes <input type="checkbox"/> no		ATTORNEY DOCKET NO	
Verified and Acknowledged Examiners initials		843 41106X00			
TITLE : Semiconductor device, method of measuring the same, and method of manufacturing the same					

<b>NOTICE OF ALLOWANCE MAILED</b>		<b>CLAIMS ALLOWED</b>	
		Total Claims	Print Claim for O.G
<b>ISSUE FEE</b>		<b>DRAWING</b>	
Amount Due	Date Paid	Sheets Drwg.	Figs.Drwg. Print Fig.
<input type="checkbox"/> <b>TERMINAL DISCLAIMER</b>		Application Examiner	
		<b>PREPARED FOR ISSUE</b>	
<b>WARNING:</b> The information disclosed herein may be restricted. Unauthorized disclosure may be prohibited by the United States Code Title 35, Sections 122, 181 and 368, Possession outside the U.S. Patent & Trademark Office is restricted to authorized employees and contractors only.			

FILED WITH: ☐ DISK (CRF) ☐ CD-ROM  
(Attached in pocket on right inside flap)